

Figures

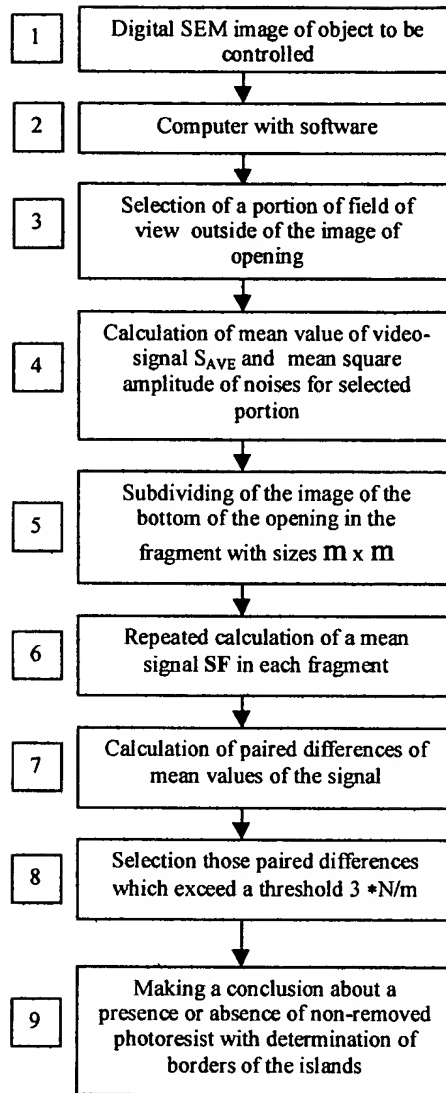


Figure 1.

A block diagram illustrating a sequence of actions during performing the inventive method for controlling a completeness of removal of a resistive layer in narrow openings-windows of a photoresist layer

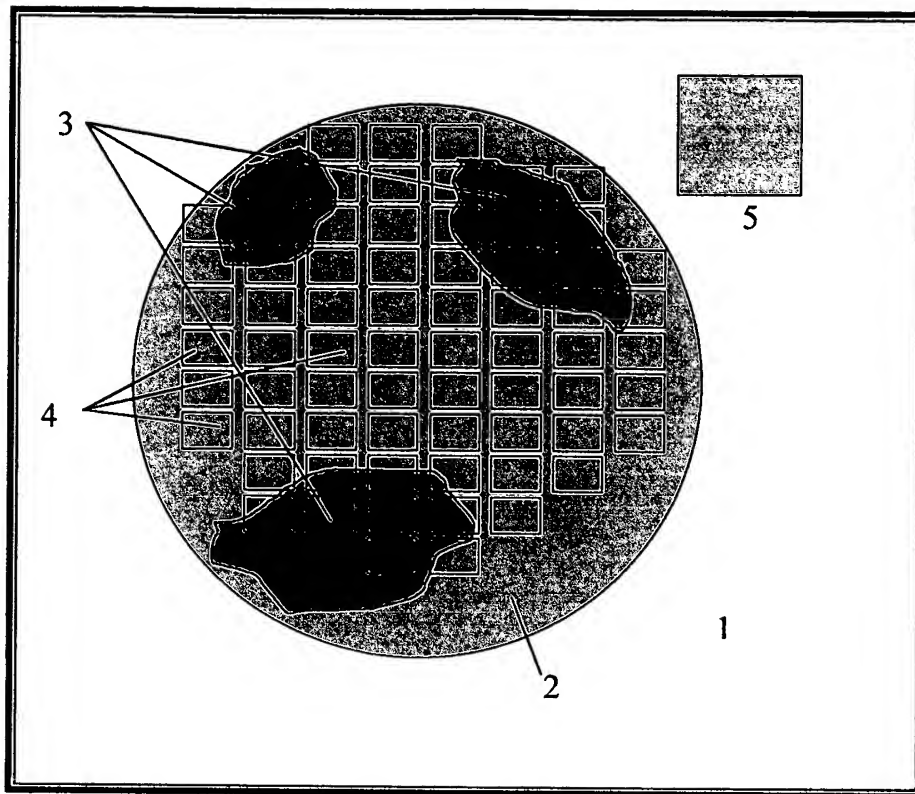


Figure 2

A view schematically showing a scan electron microscope image of a structure which contains a round opening.

1 is a microscope field of view; 2 is a bottom of the opening; 3 are islands of non-removed photoresist; 4 are image fragments for video-signal mean value **SF** calculation; 5 is a portion of field of view for mean square amplitude of noises **N** calculation.